

# ***X-ray imaging with a silicon microstrip detector coupled to the RX64 ASIC***

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# Outline

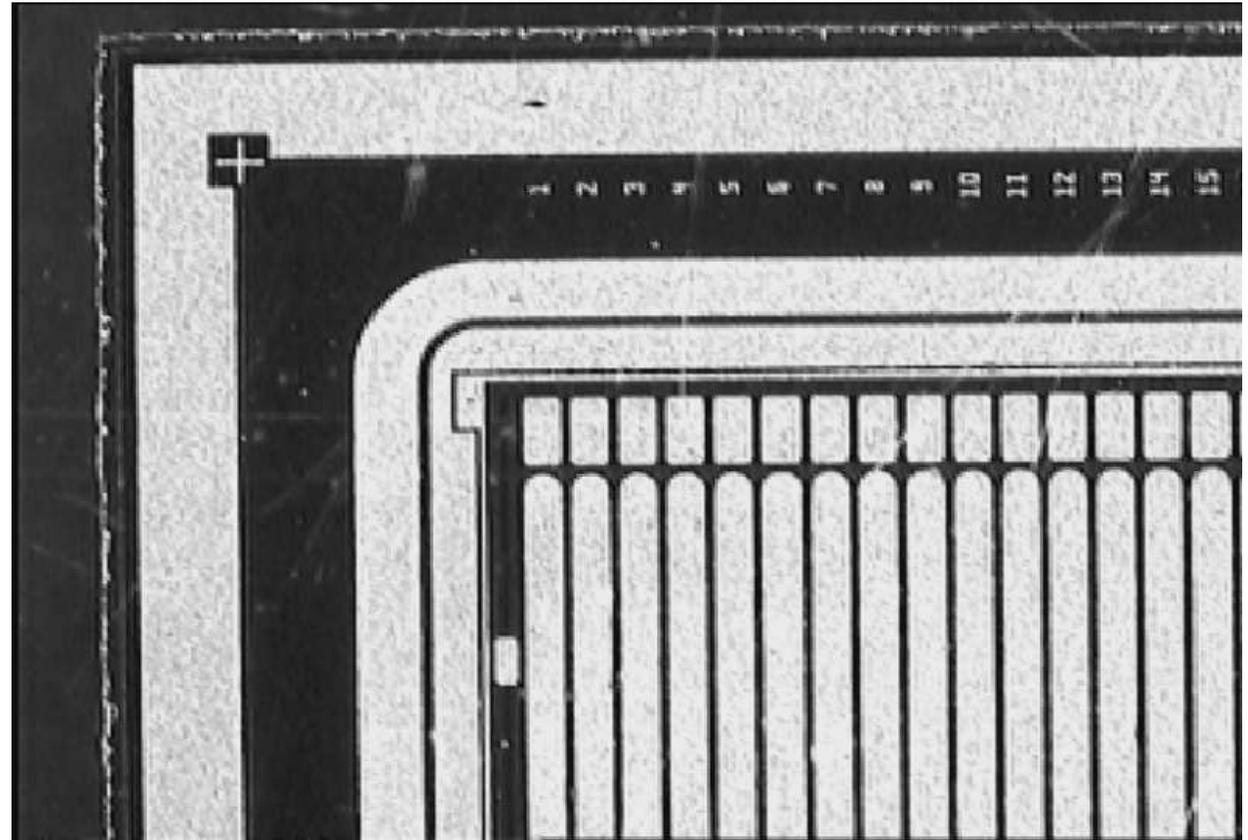
- Motivation and intended applications
- System description
  - ⇒ Microstrip detectors
    - *Good spatial resolution (100  $\mu\text{m}$  pitch)*
  - ⇒ RX64 readout chip for single photon counting
    - *Low noise (designed for crystallography @ 8 keV)*
    - *High counting rate*
- Measurements:
  - ★ *RX64 internal calibration*
    - ⇒ Gain estimation
    - ⇒ Noise measurement
  - ★ *Radioactive sources* ⇒ Gain measurement, absolute energy scale
  - ★ *Quasi-monochromatic X-ray beam*
    - ⇒ Energy scans
    - ⇒ Imaging tests

# *Motivation and applications*

- One-dimensional silicon array for scanning mode imaging
  - ⇒ Good spatial resolution with reduced number of channels
- Advantages of digital (single photon) X-ray imaging:
  - ⇒ Higher detecting efficiency with respect to screen-film systems
    - *Edge-on orientation (parallel incidence) preferred for  $E > 18$  keV*
  - ⇒ Possibility of processing and transferring digital data
  - see also talk by P. Rato Mendes (normal incidence scanning)
- Subtraction imaging: removes background structures
- Dual energy technique: isolates materials characterized by different energy dependence of linear attenuation coeff.  $\mu$ 
  - **First application: angiography at iodine K-edge (33 keV)**
  - **Another application: dual-energy mammography (18+36 keV)**
  - **Suitable for small-scale installations**

# *Silicon microstrip detectors*

- 132 strip detector for 1<sup>st</sup> prototype (2 RX64 chips)
  - AC-coupled strips
  - FOXFET biasing
  - Depth = 300  $\mu\text{m}$
  - Strip pitch = 100  $\mu\text{m}$
  - Strip length = 10 mm
- 400 strip detector for 2<sup>nd</sup> prototype (equipped with 6 RX64 chips)
- Detectors developed by ITC-IRST, Trento, Italy

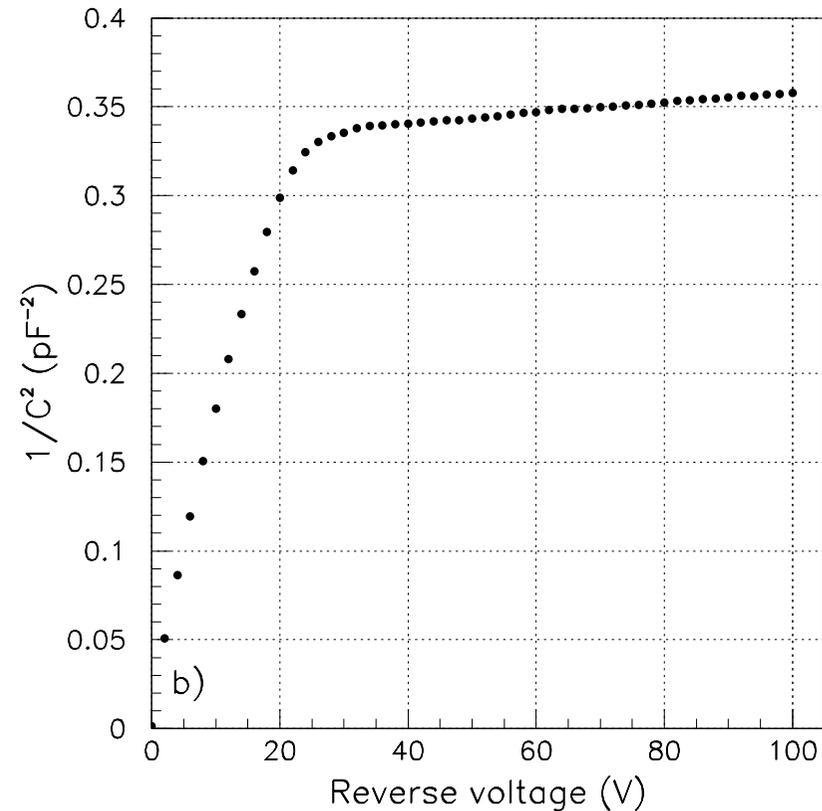
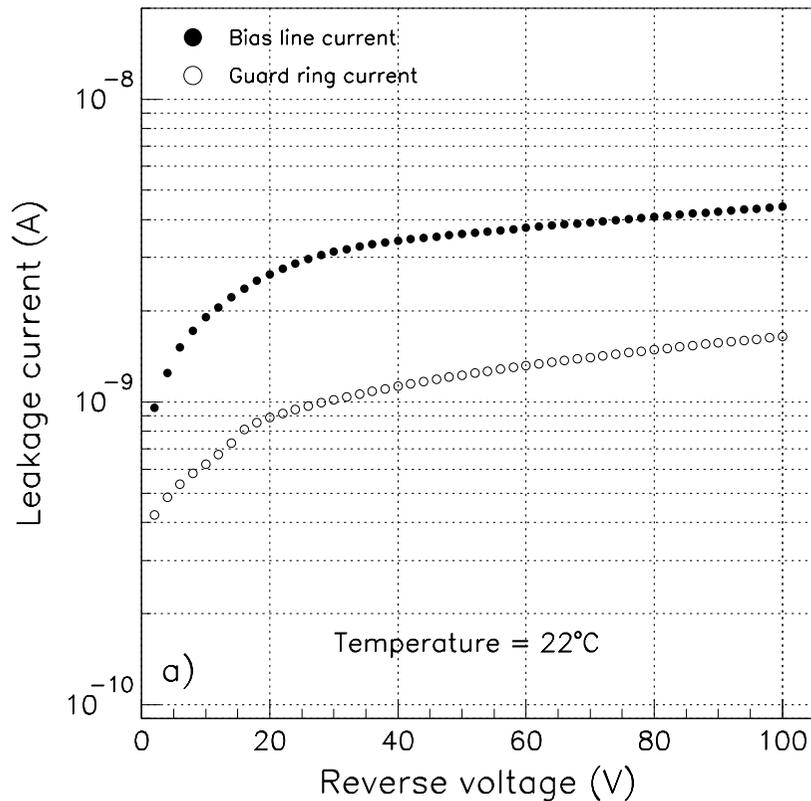


guard ring      bias line      first strip

# Detector characterization

132 strip detector

400 strip detector



**I–V for bias line and guard ring**

**Leakage current (typ.) for 128–400 strip det.**

at 30 V  $\approx$  24 – 33 pA/strip (22–25 °C)

at 60 V  $\approx$  28 – 44 pA/strip

**C–V for a group of 4 strips**

**Depletion voltage  $\approx$  25 V**

# Detecting efficiency

Efficiency for converting X-rays via photoelectric effect

## Front configuration

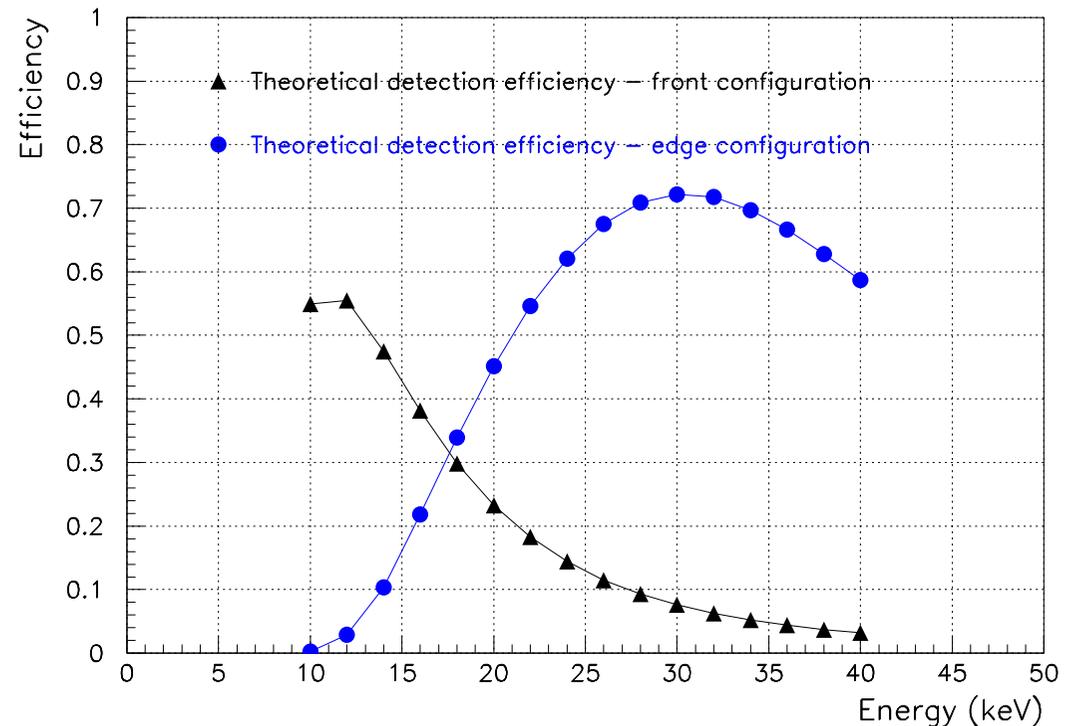
→ Strip orthogonal to beam axis

- 70  $\mu\text{m}$  of Al absorber
- 300  $\mu\text{m}$  active length

## Edge configuration

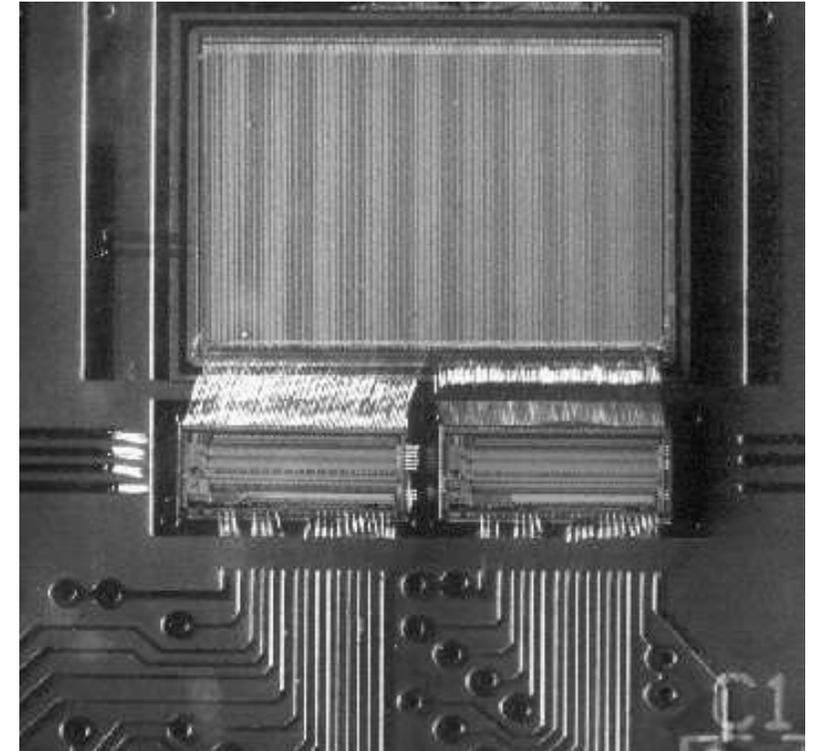
→ Strip parallel to beam axis

- 765  $\mu\text{m}$  of insensitive Si
- 10 mm active length



# The *RX64* readout chip

- Binary architecture for readout electronics
  - preamp. + shaper (tunable peaking time) + discrim. + scaler : 1 bit information per strip
  - Single photon counting (up to 1 M per strip)
- 64 channels – AMS 0.8  $\mu\text{m}$  technology
  - 2 chips (128 channels) in the 1<sup>st</sup> prototype, 6 chips (384 channels) in the 2<sup>nd</sup> prototype
  - Low noise (min. threshold 6 keV)*
  - Counting rate* capability = 200 kHz/channel



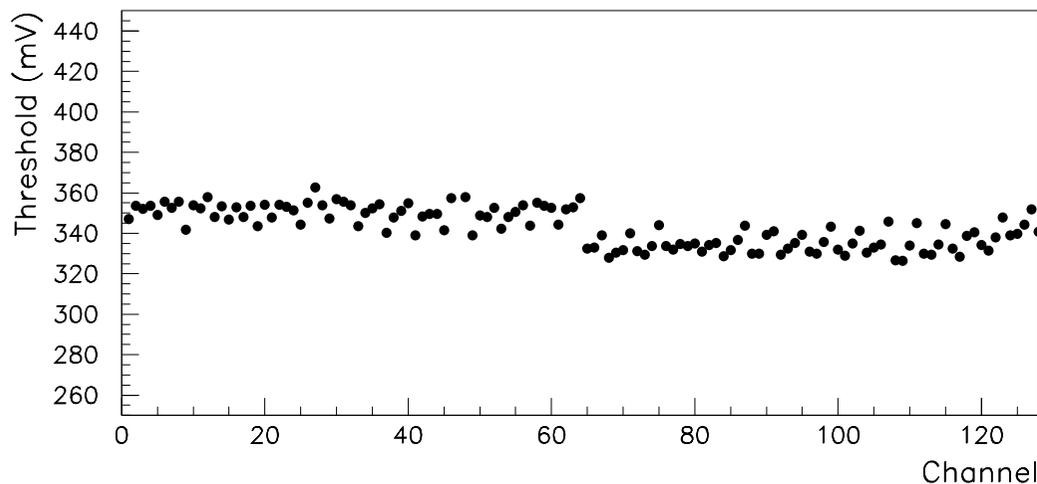
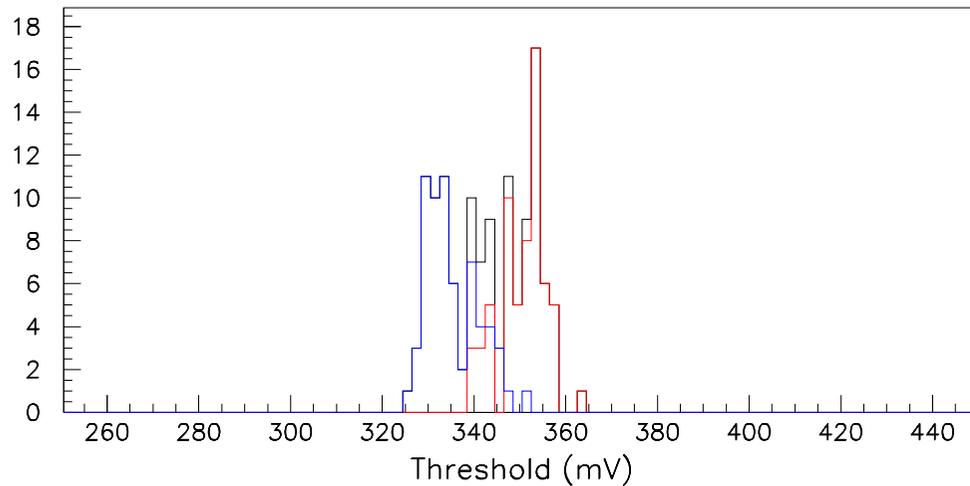
Parameter	Measured value
Gain	60-90 $\mu\text{V}$ /electron
ENC ( $C_{det}=2.5$ pF, $I_{det}=100$ pA)	167 el. RMS
Input range	up to 10000 el.
Peaking time	500-1000 ns
Counting rate	200 kHz/channel
Power consumption	2.5 mW/channel

## *Data Acquisition:*

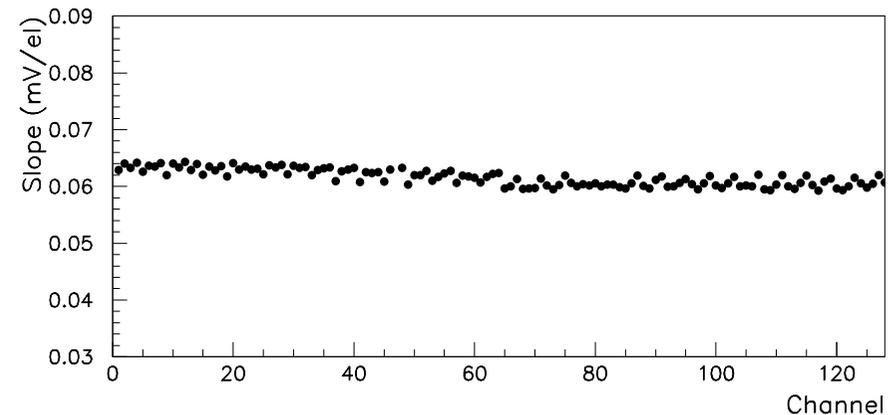
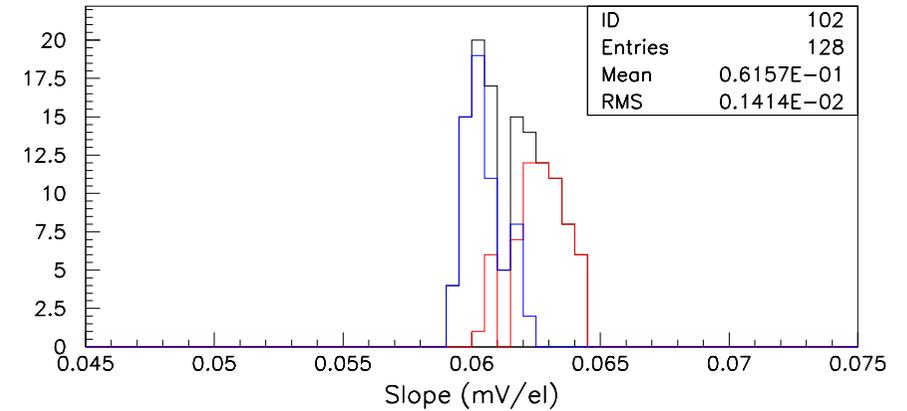
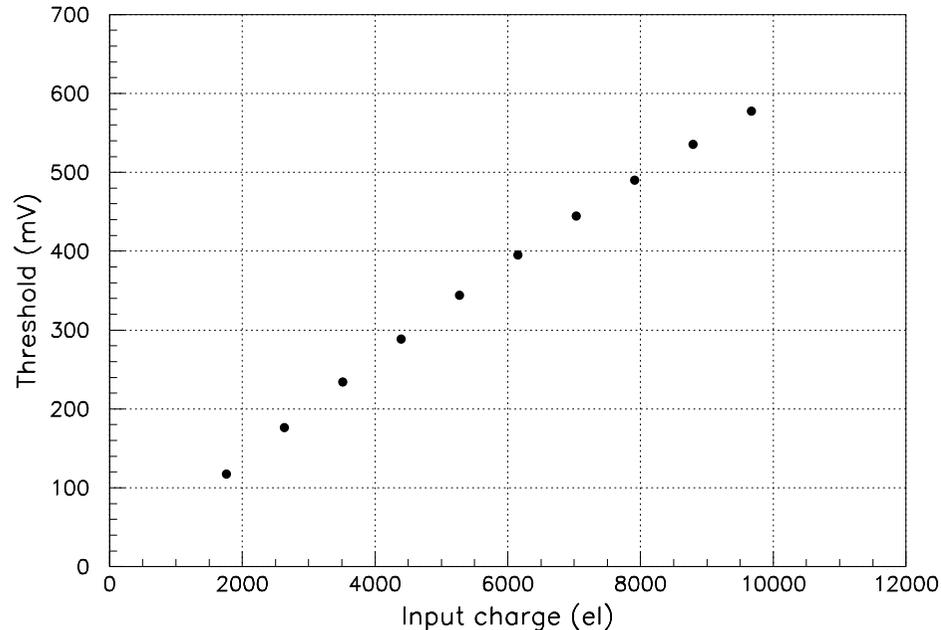
- NI's PCI-DIO-96 (desktop) or DAQCard-DIO-24 (portable)
- NI's LabVIEW 6i software

# Measurements with internal calibration

- Calibration pulse of  $\approx 5300$  electrons (internal voltage step applied to  $C_{\text{test}} = 75$  fF)
- Measure counts vs. threshold (noise ends at 80 mV)
- Gaussian fit to differential distr. gives signal amplitude and noise at discrim. output
- Gaussian peak threshold distribution for 128 channels:
  - ➔ Threshold spread  $\approx 8\%$
  - ➔ Small systematic difference ( $\approx 4\%$ ) between the chips



# Response linearity, gain estimation



- Scan with 10 different amplitudes (4–22 mV)
- Circuit response linear up to 8000 electrons (30 keV) for  $T_{\text{peak}} = 1 \mu\text{s}$
- Linear fit: gain and comparator offset

$$\langle \text{Gain} \rangle = 61.6 \pm 1.4 \mu\text{V/el.}$$

Small (3.5%) systematic difference between chips

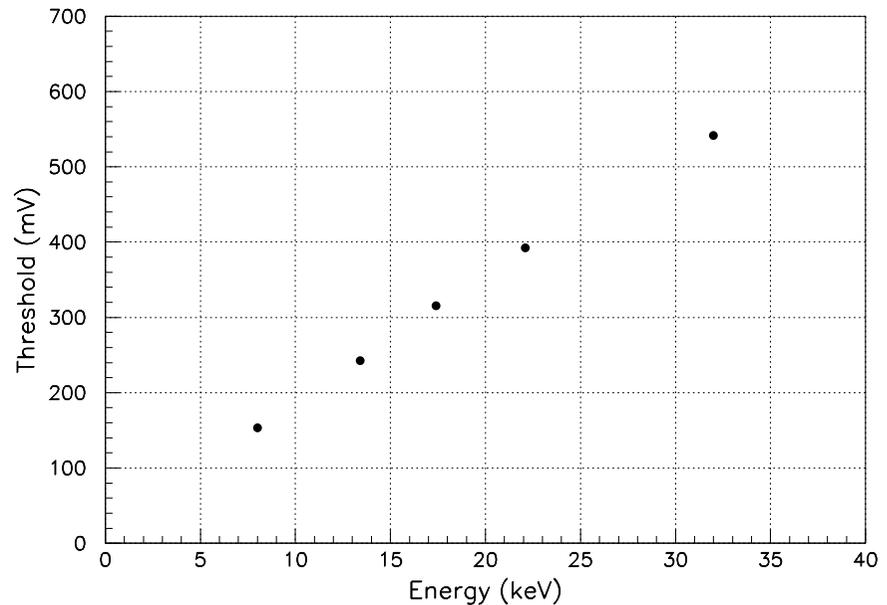
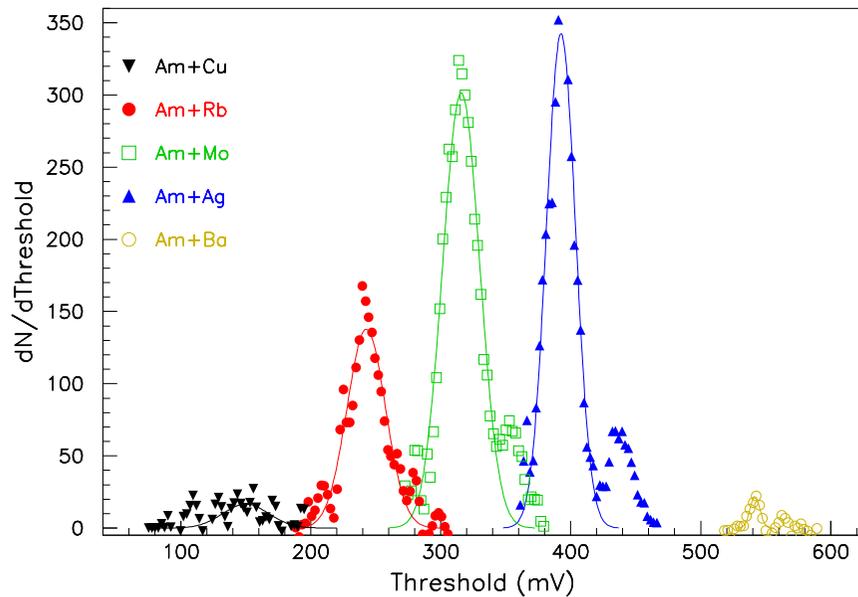
# Noise measurements

*Detector with 128 equipped channels:*

- *RMS value of noise = 8.1 mV  $\Rightarrow$  ENC = 131 electrons*
- *RMS of comparator offset distribution 3.2 mV: 2 times smaller than noise (common threshold setting for all channels)*

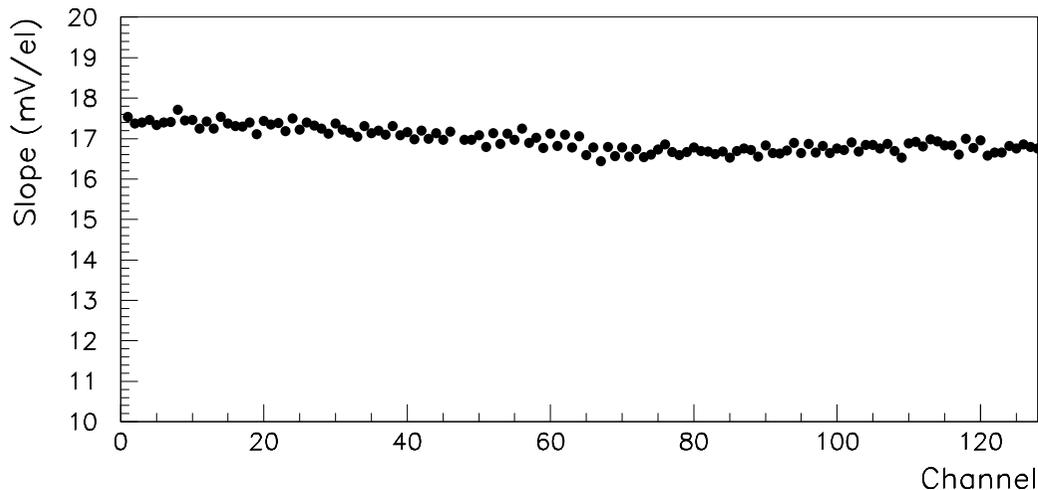
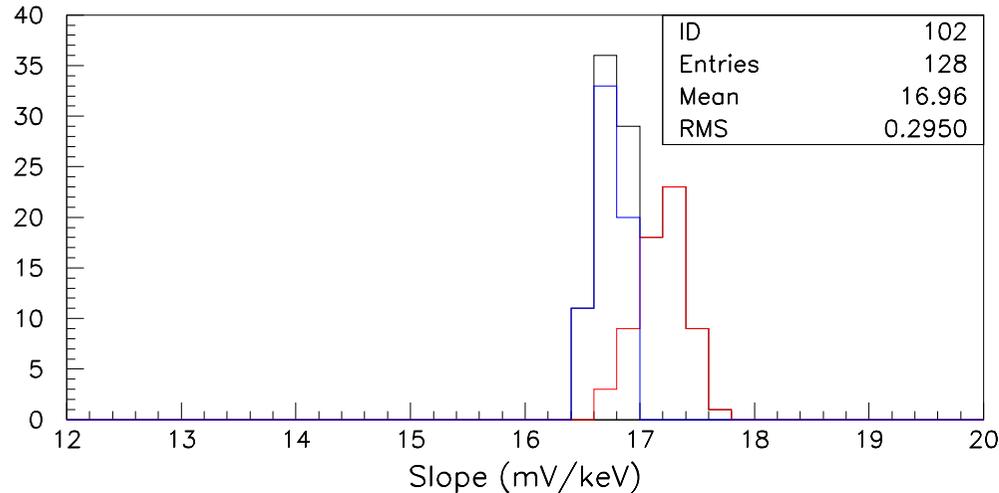
Module	T(peak)	Gain ( $\mu$ V/el.)	ENC (electrons)
2xRX64+detector	LONG	61.6	131
6xRX64 alone	LONG	63.7	176
	SHORT	82.8	131
6xRX64+fanout (no detector)	LONG	63.7	184
	SHORT	82.8	148

# Results with $^{241}\text{Am}$ fluorescence source



- $K_{\beta}$  peak clearly visible for Mo, Ag and Ba targets
- Gaussian fits to  $K_{\alpha}$  peak give absolute energy calibration
  - ➔ RMS noise (from Ag) = 11.2 mV  $\Rightarrow$  ENC  $\approx$  180 electrons
    - Due to fluctuations in  $e-h$  pairs + higher strip bias voltage

# Gain evaluation with source



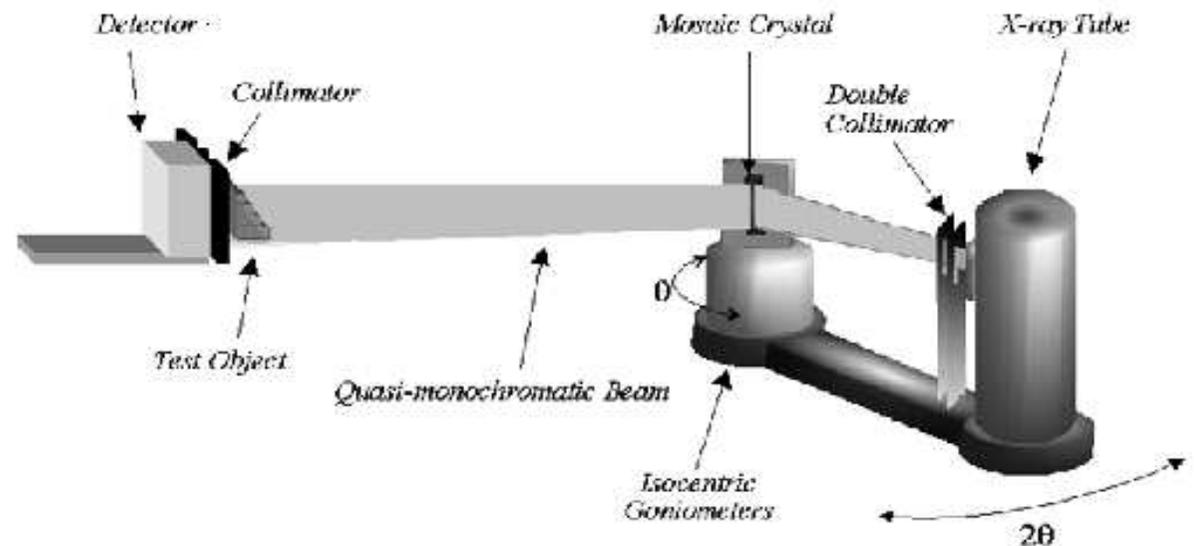
- Linear fit in the range  $8 < E < 30$  keV (excl. Am–Ba)
- Gain distribution for the 128 channels
  - ⇒  $\langle \text{Gain} \rangle = 17.0$  mV/keV  
⇒  $61.7$   $\mu$ V/el.
  - ⇒ RMS gain =  $0.3$  mV/keV
  - ⇒ Small (2.7%) systematic difference between the two chips
- Good agreement with the gain extracted using the internal calibration

# Quasi monochromatic X-ray beam

- W-anode X-ray tube
- X-ray beam monochromatized by Bragg diffraction in a mosaic crystal
  - $2.8 \times 6.0 \times 0.1 \text{ cm}^3$  highly oriented pyrolytic graphite crystal
- ⇒ X-ray tube mounted on a goniometer
  - X-ray energy selection
- ⇒ Possibility of dual energy beams (using 2<sup>nd</sup> order Bragg diffraction)

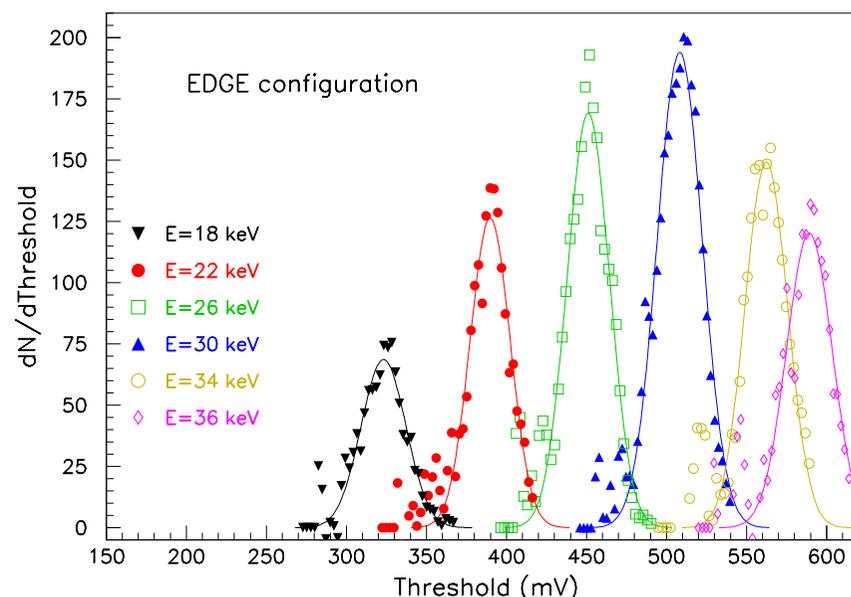
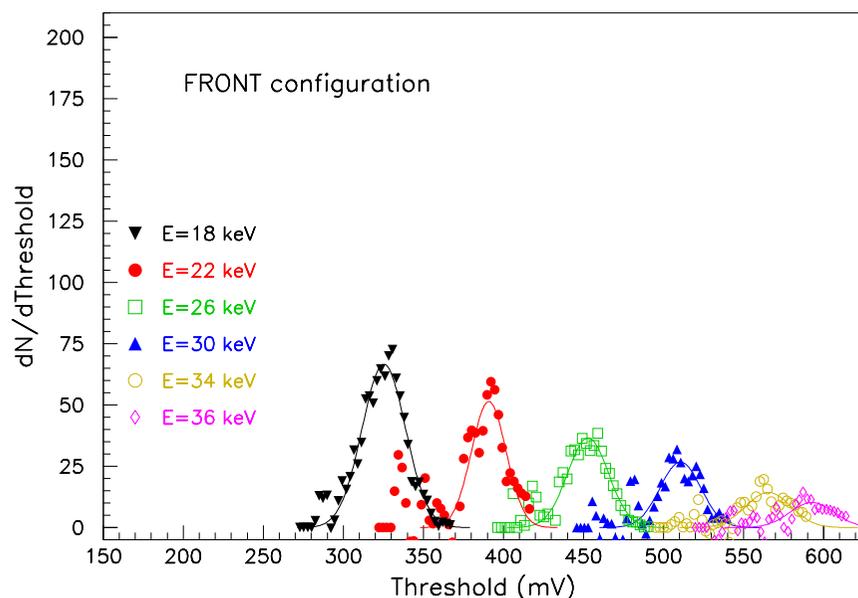
$$E_B = \frac{n \cdot h \cdot c}{2d \sin \vartheta_B}$$

- Detector placed at  $\approx 90 \text{ cm}$  from the crystal
- $300 \mu\text{m}$  wide collimator upstream from the detector (FRONT config. only)



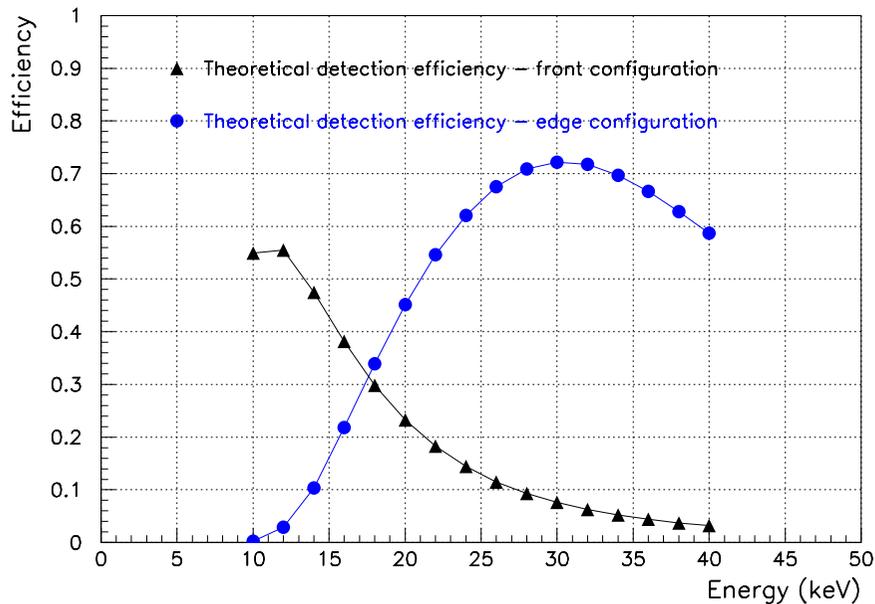
# *Energy scans with X-ray beam*

- Discriminator threshold scans taken with 6 different energies of the quasi-monochromatic X-ray beam



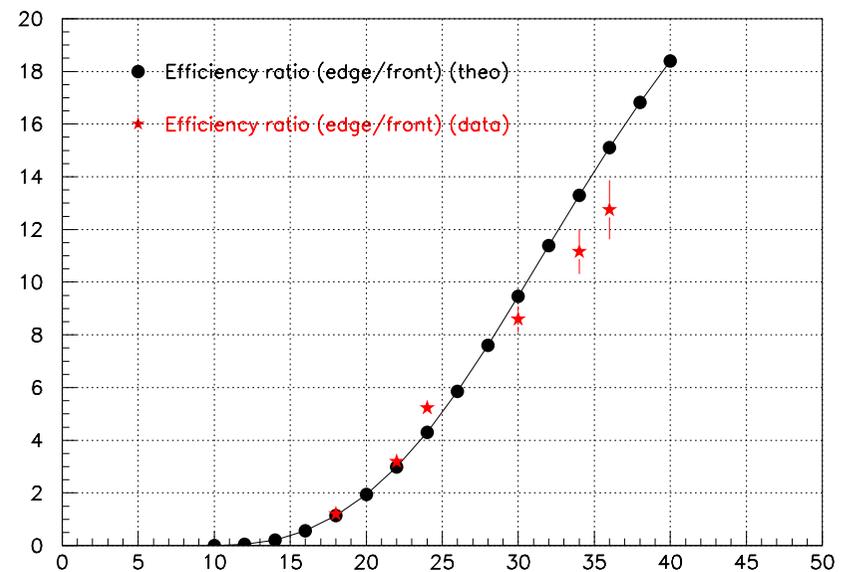
- Detector much more efficient in the edge configuration in the whole energy range considered (18–36 keV)
- Rate capability: at 20 keV, counts  $\propto$  mAs (5–225 mAs), with at least a factor of 10 margin before saturation

# Measured detector efficiency



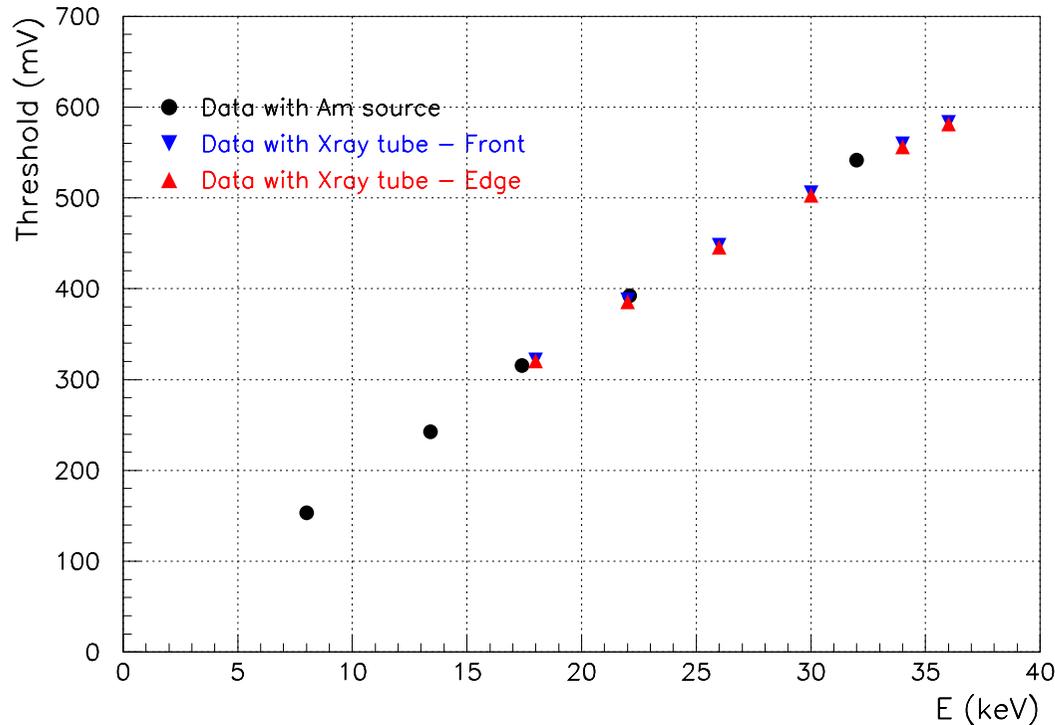
**Theoretical efficiencies as a function of energy in front and edge configurations**

**Efficiency ratio Edge/front**



- Acceptable agreement between data measured and theoretical expectations (Compton neglected)

# Energy scan results



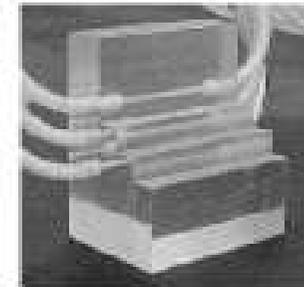
- Excellent agreement among the different data sets
  - Quality of the tuning of the quasi monochromatic X-ray beam
- Gaussian width  $\approx 13.4$  mV (was 11.2 mV with Am-Ag source)
  - *Enlargement reflecting the energy spread of the quasi-monochromatic beam*

# *K-edge subtraction angiography*

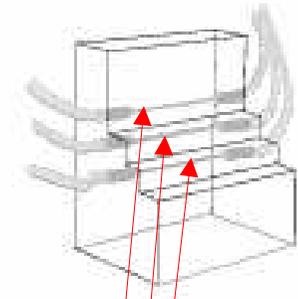
- Medical examination → visualization of occlusions in arteries
- Conventional procedure for angiography
  - ⇒ Iodate contrast medium injected directly in the coronary arterial system
    - *Catheter fitted in the femoral artery → invasive procedure (high risk)*
    - *Long fluoroscopy exposure time to manage the catheter up to the heart*
  - ⇒ X-ray transmission image taken
    - *Iodine X-ray absorption coefficient different from the surrounding tissues*
- K-edge subtraction angiography (usually at synchrotron facility)
  - ⇒ TWO images taken with two monochromatic beams
    - *1<sup>st</sup> BELOW and 2<sup>nd</sup> ABOVE the iodine K-edge (at 33.13 keV)*
  - ⇒ Pixel by pixel subtraction of the two images to extract the iodine signal
    - ***Enhanced contrast:*** → *lower Iodine concentration needed*  
→ *possible intravenous injection of the contrast agent*

# Imaging test

- Detector in edge configuration
- Test object
  - ⇒ plexiglass step wedge phantom
    - 40 mm high – 30 mm wide
    - Thickness ranging from 10 to 45 mm
  - ⇒ Three 1 mm diameter cylindrical cavities
    - Filled with iodate solution
    - Solution concentration = 370 mg/ml
- Images taken with quasi-monochromatic beam
  - ⇒ First image at 31 keV
  - ⇒ Second image at 35 keV
- Two dimensional image obtained by moving the object in the orthogonal direction



a)



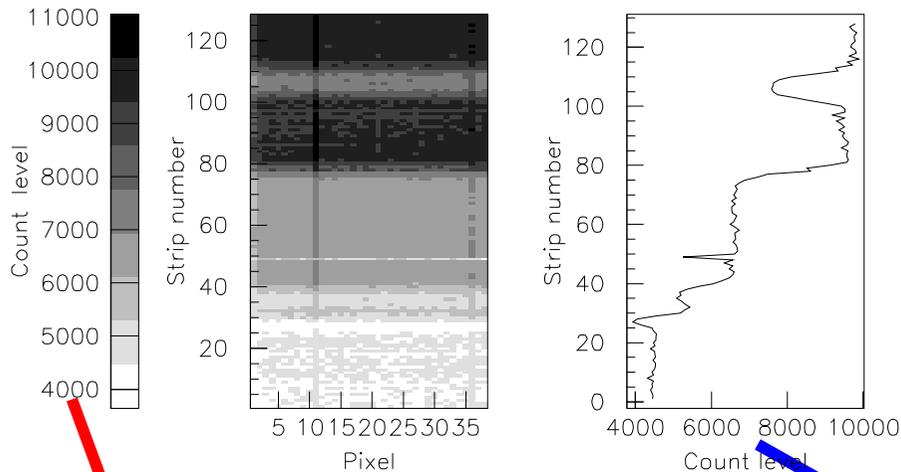
b)

Cavities filled with iodine

# Single energy images

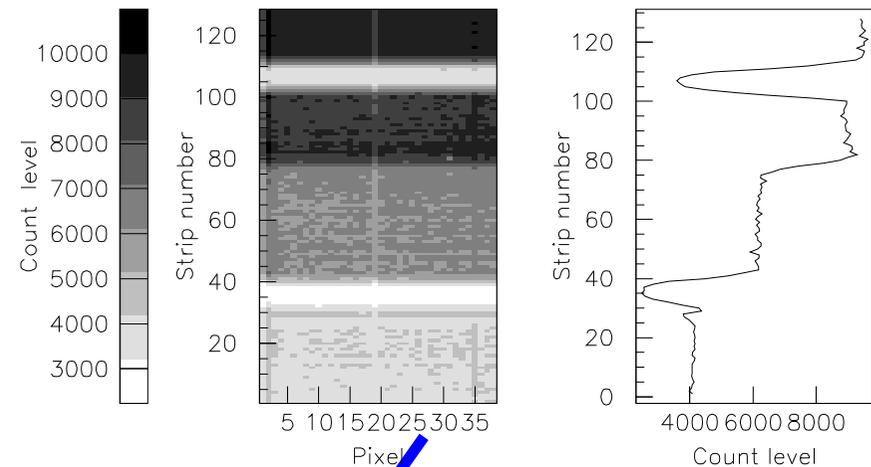
- Data corrected for X-ray beam intensity profile, flux differences at the two energies and detector efficiency

*Image at 31 keV*



*Iodine signal hardly visible at 31 keV*

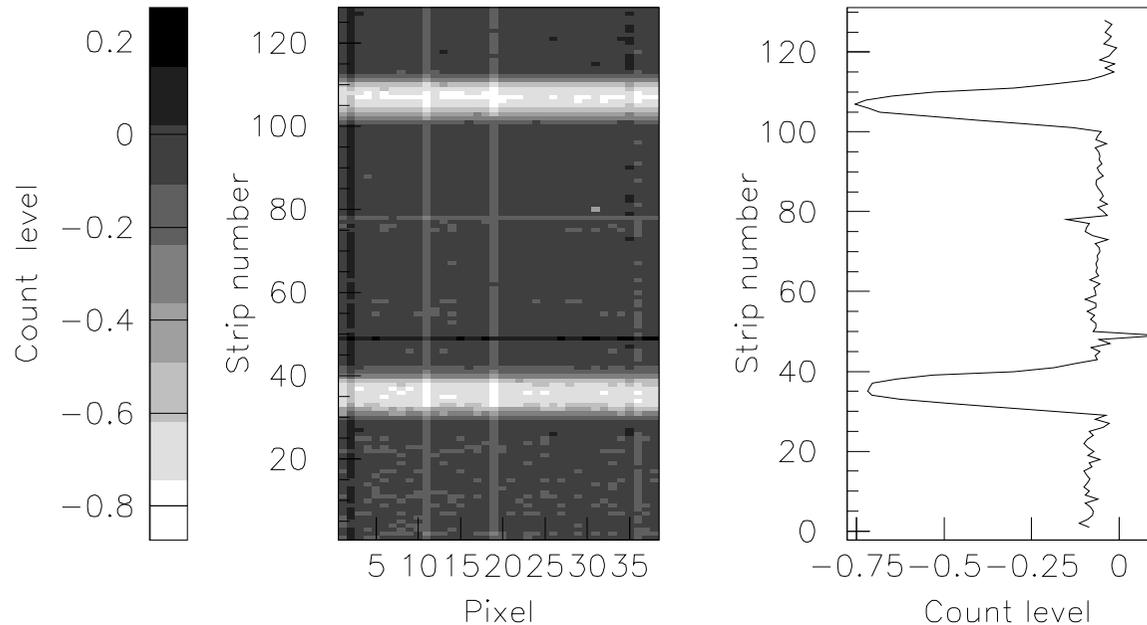
*Image at 35 keV*



*Presence of a vertical gradient due to the attenuation characteristics of the step-wedge phantom*

# *K-edge subtraction image*

$$\text{Subtraction image} = \ln(\text{Image}_{35}) - \ln(\text{Image}_{31})$$



- No gradient due to the attenuation characteristics of the phantom
- Iodine contrast enhanced
  - ➔ Detail visibility improved

# *Conclusions and outlook*

- Detecting system for X-ray imaging (8–36 keV) developed and tested
  - ⇒ Gain and noise measured with chip calibration and fluorescence sources
    - $\langle \text{Gain} \rangle = 17.0 \text{ mV/keV} \Leftrightarrow 61.6 \text{ } \mu\text{V/el.} @ T(\text{peak}) = 1 \text{ } \mu\text{s}$
    - $\text{Noise threshold} \approx 80 \text{ mV} \Leftrightarrow 4.7 \text{ keV} \Rightarrow \text{operation with threshold as low as } 6 \text{ keV}$
    - $\text{ENC} \approx 131 \text{ electrons (1 cm long strips, 128 equipped channels)}$
- Energy scans with quasi-monochromatic X-ray beam
  - ⇒ X-ray energy in excellent agreement with the expectations
  - ⇒ Energy spread small with respect to the intrinsic noise of the system
- K-edge subtraction angiography test (128 equipped channels)
  - ⇒ Contrast enhanced + background structure removed
- Work in progress towards clinical applications:
  - *Larger detectors (400 strips: under test; 4 cm length) + double threshold chips*
  - *Large field dichromatic X-ray source for clinical angiography*